Exhibit 3



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(45) Date of Patent: Sep. 16, 2003

(54) CIRCUIT WITH INTERCONNECT TEST UNIT AND A METHOD OF TESTING INTERCONNECTS BETWEEN A FIRST AND A SECOND ELECTRONIC CIRCUIT

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U.S.C. 154(b) by 0 days.

09/402,154 (21) Appl. No.: (22) PCT Filed: Jan. 29, 1999 (86) PCT No.: PCT/IB99/00172

§ 371 (c)(1),

(2), (4) Date: Sep. 29, 1999

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PCT Pub. Date: Aug. 5, 1999

Foreign Application Priority Data (30)

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Feb. 22, 1998	(EP)	98200288
Nov. 30, 1998	(EP)	98204042

(51) Int. Cl.⁷ G01R 31/28

(58)	Field of Search	702/57–59, 108,
	702/117, 118; 324/500	, 512, 527; 326/16,
	106; 714/FOR 100, 25	5, 27, 30, 718, 719,
		726, 727, 733

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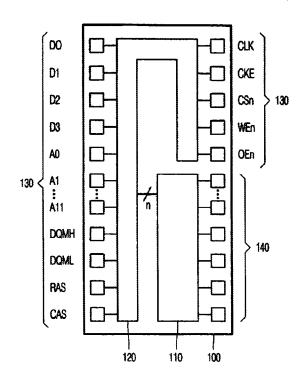
* cited by examiner

Primary Examiner—Marc S. Hoff Assistant Examiner—Craig Steven Miller

(57)**ABSTRACT**

An electronic circuit comprises a plurality of input/output (I/O) nodes for connecting the electronic circuit to a further electronic circuit via interconnects. A main unit implements a normal mode function of the electronic circuit. A test unit tests the interconnects. The electronic circuit has a normal mode in which the I/O nodes are logically connected to the main unit and a test mode in which the I/O nodes are logically connected to the test unit. In the test mode the test unit is operable as a low complexity memory via the I/O nodes.

13 Claims, 3 Drawing Sheets





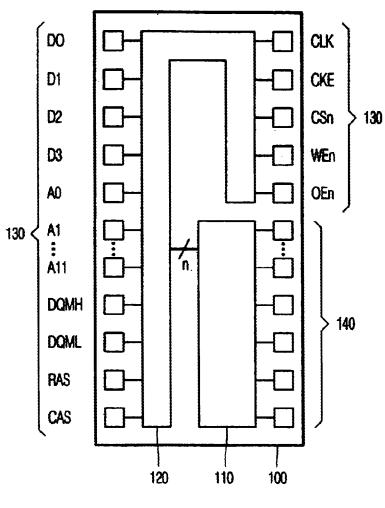


FIG. 1

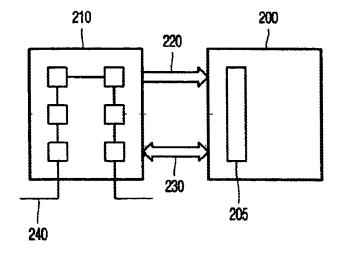


FIG. 2



Sep. 16, 2003

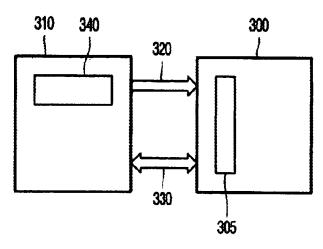


FIG. 3

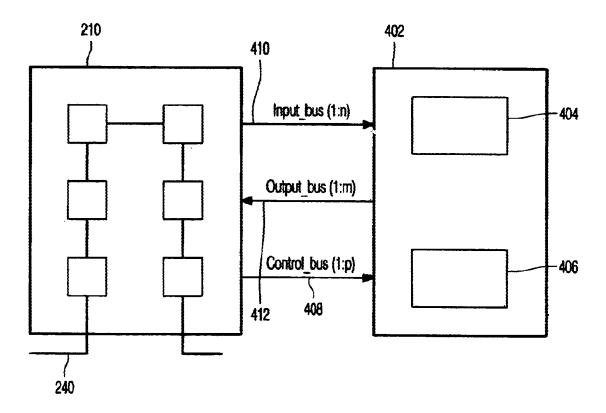


FIG. 4

Sep. 16, 2003

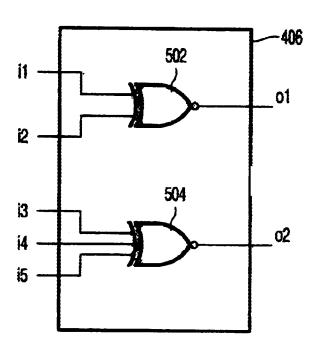


FIG. 5

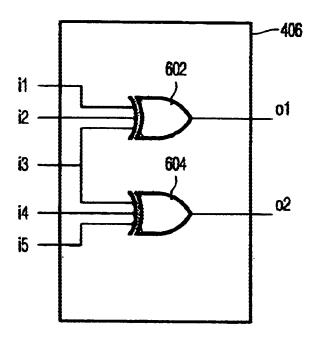


FIG. 6

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